FORM PTO-1449 (REV.7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. A 856063.547D1			APPLICATION NO.			
INE	NDM.	ATION DISCLOSU	APPLICANTS Salvatore Lombardo et al.								
LVF)KIVI	(Use several sheets if necessary)			FILING DATE GROUP ART UNIT July 7, 2003			P ART UNIT			
U.S. PATENT DOCUMENTS											
*EXAMINER DOCUMENT NUMBER DATE			· · · · · · · · · · · · · · · · · · ·	NAME		CLASS SUBCLAS		SUBCLASS	FILING DATE IF APPROPRIATE		
A.S.	AA	4,343,080	08/10/82	Hataishi et al.		29		571	/		
1	AB	5,028,557	07/02/91	Tsai et al.		437		59			
	AC	5,126,278	06/30/92	Kodaira		437		24		T	
	AD	5,635,423	06/03/97	Huang et al.		437		195		7	
-	ΑĒ	5,659,201	08/19/97	Wolleson		257		758			
	AF	5,712,177	01/17/98	Kaushik e	437		42				
	AG	5,753,967	05/19/98	Lin		257		635			
	AH	5,643,825	07/01/97	Gardner et al.		437		70			
	Al	5,814,555	09/29/98	Bandyopadhyay et al.		438		619			
	ΔJ	5,821,149	10/13/98	Schuppen et al.		438		312			
	AK	5,847,460	12/08/98	Liou et al.		257		751			
FOREIGN PATENT DOCUMENTS											
		DOCUMENT DATE COUNTRY							TRANSLATION YES NO		
X-51	AL	03-292740	12/24/91	Japan							
1.5	AM	0697716A2	02/21/96	EP							
12	AN										
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)											
A.	AO	S. Wolf et al., "Silicon Processing for the VLSI Era V1" - Process Technology, 1986, pp									
Asi	182-183.										
\ \	Gomi et al., "A Sub-30psec Si Bipolar LSI Technology," in International Electron Devices Meeting, San Francisco, December 11-14, 1988, Institute of Electrical and Electronics										
		Engineers, No. 1988, pp 744-747, 1988.									
1	AQ	Lombardo, S. et al., "Ge Ion Implantation in Si for the Fabrication of Si/Ge Si									
Heterojunction Transistors," Materials Chemistry and Physics, 46(2-3), pp. 156-160, 1996. EXAMINER DATE CONSIDERED										1990.	
*EYAMINER: Initial Conference and Autobaccons											
* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).											